

SEMITRANSTM 3

IGBT Modules

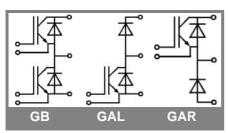
SKM 200GB173D SKM 200GB173D1 SKM 200GAL173D SKM 200GAR173D

Features

- MOS input (voltage controlled)
- N channel , Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 x I_{cnom}
- Latch-up free
- Fast & soft inverse CAL diodes
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (13 mm) and creepage distance (20 mm)

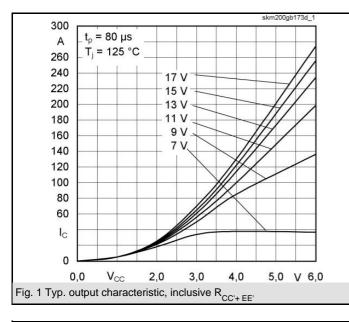
Typical Applications

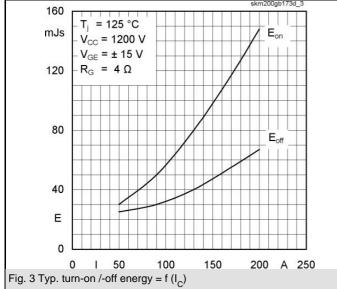
- AC inverter drives on mains 575 750 V_{AC}
- DC bus voltage 750 1200 V_{DC}
- Public transport (auxiliary syst.)
- Switching (not for linear use)

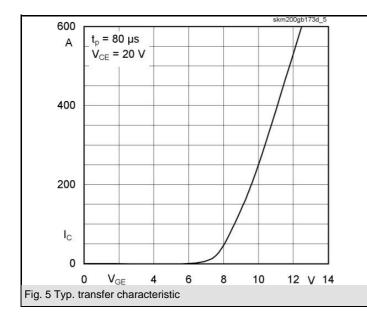


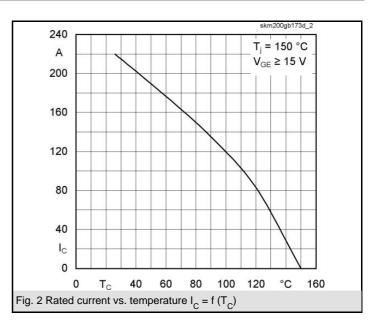
	Absolute	T _c = 25 °C, unless otherwise	s otherwise specified				
	Symbol	Conditions	Values	Units			
	IGBT						
	V _{CES}		1700	V			
1	I _C	T _c = 25 (80) °C	220 (150)	А			
	I _{CRM}	t _p = 1 ms	300	А			
	V _{GES}		± 20	V			
L	T _{vj} , (T _{stg})	$T_{OPERATION} \le T_{stg}$	- 40 + 150 (125)	°C			
L	V _{isol}	AC, 1 min.	4000	V			
	Inverse diode						
	I _F	T _c = 25 (80) °C	150 (100)	А			
	I _{FRM}	t _p = 1 ms	300	А			
	I _{FSM}	t _p = 10 ms; sin.; T _j = 150 °C	1450	А			
	Freewheeling diode						
	I _F	T _c = 25 (80) °C	230 (150)	А			
	I _{FRM}	t _p = 1 ms	400	А			
	I _{FSM}	t _p = 10 ms; sin; T _j = 150 °C	2200	А			

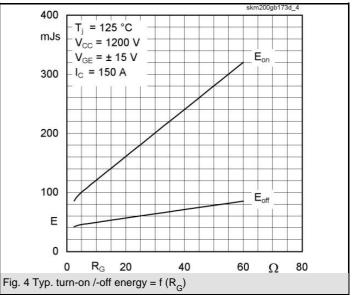
Characteristics		$T_c = 25 \text{ °C}$, unless otherwise specified				
Symbol	Conditions	min.	typ.	max.	Units	
IGBT						
V _{GE(th)} I _{CES} V _{CE(TO)}	$V_{GE} = V_{CE}, I_C = 10 \text{ mA}$ $V_{GE} = 0, V_{CE} = V_{CES}, T_j = 25 (125) ^{\circ}C$ $T_j = 25 (125) ^{\circ}C$	4,8	5,5 0,1 1,65 (1,9)		V mA V	
r _{CE}	V _{GE} = 15 V, T _j = 25 (125) °C		11,7 (17,3)	. ,	mΩ	
V _{CE(sat)}	I_{Cnom} = 150 A, V_{GE} = 15 V, chip level		3,4 (4,5)	3,9 (5)	V	
$\begin{array}{c} C_{ies} \\ C_{oes} \\ C_{res} \\ L_{CE} \\ R_{CC'+EE'} \\ t_{d(on)} \\ t_{r} \\ t_{d(off)} \\ t_{f} \\ E_{on} (E_{off}) \\ \hline \textbf{Inverse d} \\ V_{F} = V_{EC} \end{array}$	under following conditions $V_{GE} = 0$, $V_{CE} = 25$ V, f = 1 MHz res., terminal-chip T _c = 25 (125) °C $V_{CC} = 1200$ V, $I_{Cnom} = 150$ A $R_{Gon} = R_{Goff} = 4 \Omega$, $T_j = 125$ °C $V_{GE} = \pm 15$ V liode $I_{Fnom} = 150$ A; $V_{GE} = 0$ V; $T_j = 25$ (125)		20 2 0,55 0,35 (0,5) 580 100 750 40 95 (45) 2,2 (1,9)	20	nF nF nF mΩ ns ns ns mJ	
V _(TO) r _T I _{RRM} Q _{rr} E _{rr}	°C T _j = 125 () °C T _j = 125 () °C I _{Fnom} = 150 A; T _j = 25 (125) °C di/dt = 1000 A/µs V _{GE} = 0 V		1,3 4,5 60 (85) 15 (38)	1,5 6,2	V mΩ A μC mJ	
$FWD V_F = V_{EC} V_{(TO)} r_T I_{RRM} Q_{rr} E_{rr}$			2 (1,8) 1,3 3,5 75 (110) 20 (50)	2,4 1,5 4,5	V V MΩ A μC mJ	
Thermal of R _{th(j-c)} R _{th(j-c)D} R _{th(j-c)FD} R _{th(c-s)} Mechanic	characteristics per IGBT per Inverse Diode per FWD per module cal data			0,1 0,32 0,21 0,038	K/W K/W K/W	
M _s M _t w	to heatsink M6 to terminals M6	3		5 325	Nm Nm g	

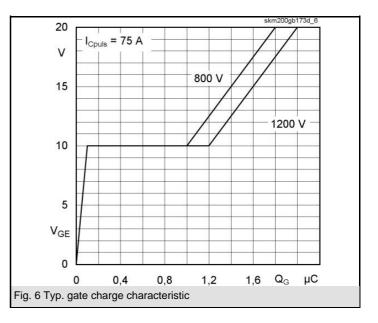


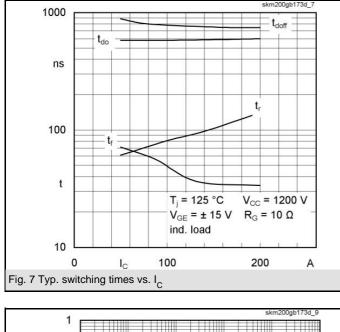


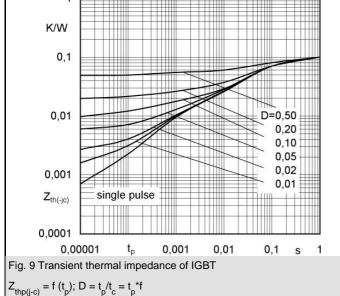


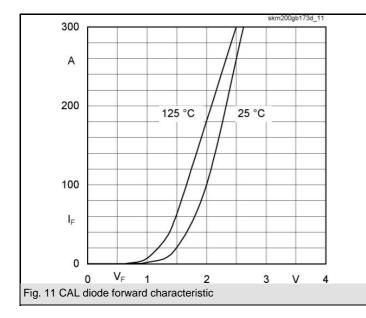


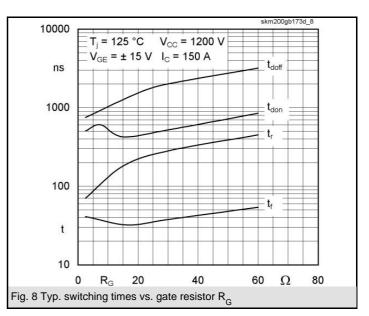


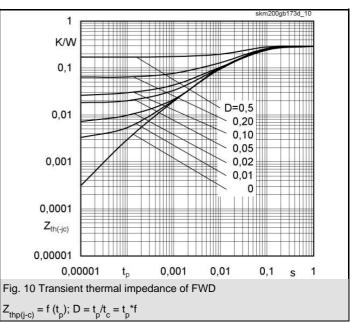


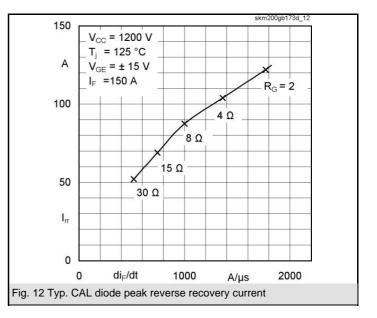


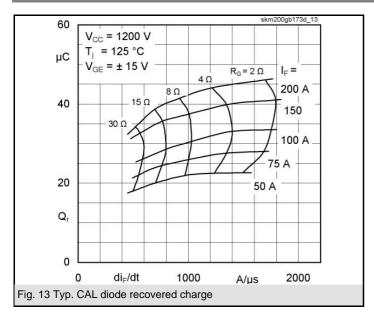


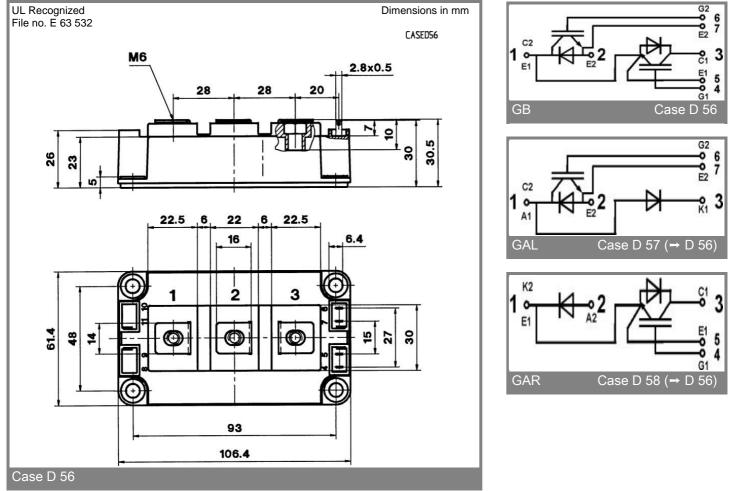












This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

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